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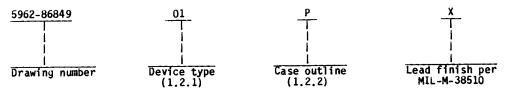
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 $1.1\,$ Scope. This drawing describes device requirements for class B microcircuits in accordance with $1.2.1\,$ of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices".

1.2 Part number. The complete part number shall be as shown in the following example:



1.2.1 Device type. The device type shall identify the circuit function as follows:

Device type

Generic number

Circuit function

01

1549

Current sensing analog latch with digital reset

1.2.2 Case outline. The case outline shall be as designated in appendix C of MIL-M-38510, and as follows:

Outline letter

Case outline

P

D-4 (8-lead, 1/4" x 3/8"), dual-in-line package

1.3 Absolute maximum ratings.

25 V dc Input supply voltage (V_S) - - - -40 V dc HI CM input voltage - -40 V dc 25 mA Storage temperature range - - - - - - - - - --65°C to +150°C +300°C 600 mW 1/ Thermal resistance, junction-to-case (θ_{JC}): (See MIL-M-38510, appendix C) Case P +175°C Junction temperature - - -

1.4 Recommended operating conditions.

Ambient operating temperature range (T_A) - - - - - - - - -55°C to +125°C

/ Derate linearly above $T_A = +25^{\circ}C$ at 5.0 mW/ $^{\circ}C$.

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2. APPLICABLE DOCUMENTS

2.1 Government specification and standard. Unless otherwise specified, the following specification and standard, of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.

SPECIFICATION

MILITARY

MIL-M-38510 - Microcircuits, General Specification for

STANDARD

MILITARY

MIL-STD-883 - Test Methods and Procedures for Microelectronics

(Copies of the specification and standard required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

- 2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.
 - 3. REQUIREMENTS
- 3.1 Item requirements. The individual item requirements shall be in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices" and as specified herein.
- $3.2\,$ Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-M-38510 and herein.
 - 3.2.1 Terminal connections. The terminal connections shall be as specified on figure 1.
 - 3.2.2 Block diagram. The block diagram shall be as specified on figure 2.
 - 3.2.3 Case outline. The case outline shall be in accordance with 1.2.2 herein.
- 3.3 Electrical performance characteristics. Unless otherwise specified, the electrical performance characteristics are as specified in table I and apply over the full recommended ambient operating temperature range.
- 3.4 Marking. Marking shall be in accordance with MIL-STD-883 (see 3.1 herein). The part shall be marked with the part number listed in 1.2 herein. In addition, the manufacturer's part number may also be marked as listed in 6.4 herein
- 3.5 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in 6.4. The certificate of compliance submitted to DESC-ECS prior to listing as an approved source of supply shall state that the manufacturer's product meets the requirements of MIL-STD-883 (see 3.1 herein) and the requirements herein.
- 3.6 Certificate of conformance. A certificate of conformance as required in MIL-STD-883 (see 3.1 herein) shall be provided with each lot of microcircuits delivered to this drawing.
- 3.7 Notification of change. Notification of change to DESC-ECS shall be required in accordance with MIL-STD-883 (see 3.1 herein).

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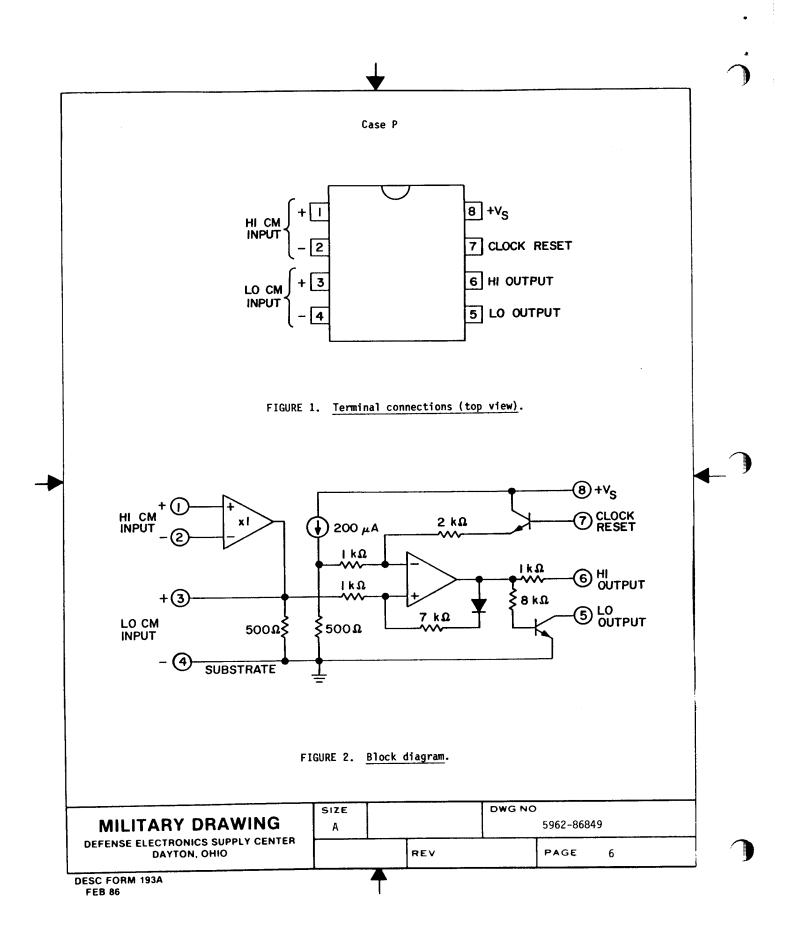
Test	 Symbol	Conditions 1/	Group A			_ Unit
		-55°C < TA < +125°C unless otherwise specified	subgroups	Min	Max	
CM INPUT	_ ,				 -	
Threshold voltage	AL41	Pins 1 and 2 shorted, $T_J = +25^{\circ}C$	1	80	120	mV
Input impedance	ZIN	 V(pin 3) = 50 mV, T _J = +25°C 	4	400	600	Ω
HI CM INPUT						
Threshold voltage	V _{T.12}	V _{CM} = 2.0 V, pin 3 open, T _J = +25 C	1	 70 	120 	ν
	A ^{LH3}	V _{C.4} = 40 V, pin 3 open, T _J = +25°C	1	70 	120	mV
Input current	IIN1	V(pin 1) = V(pin 2) = 40 V, T _J = +25°C	1	 	300 	μА
CLOCK RESET						
Minimum trigger voltage	VTRIG		1, 2, 3	! 	2.5	٧
Input current	IIN2	V(pin 7) = 4.0 V	1, 2, 3	! ! !	40	μА
HI OUTPUT					.	
Off voltage	VOFF(HI)		1, 2, 3	! !	0.1	٧
On voltage	AON(HI)	I _L = 1.0 mA	1, 2, 3	2.8		٧
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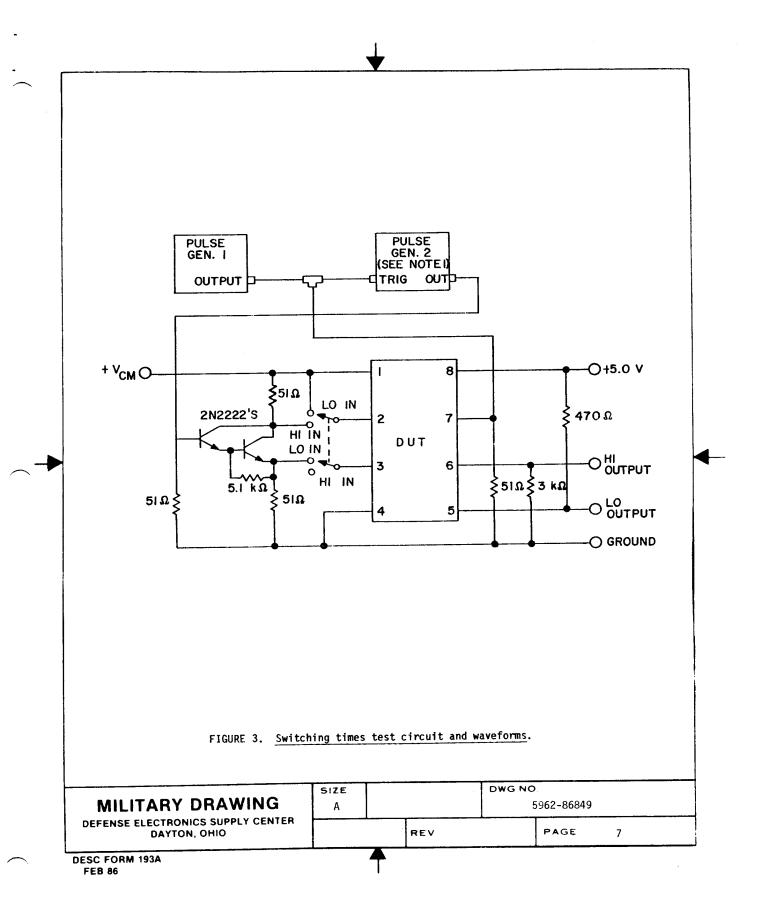
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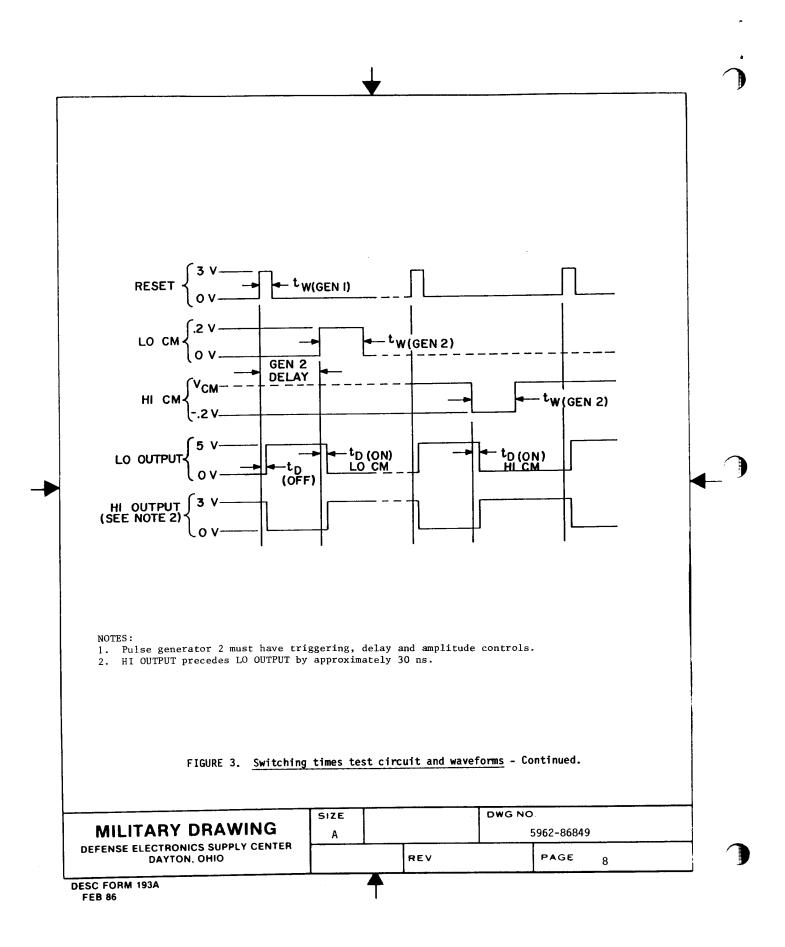
		1	Unit		
Test	Symbol	Conditions 1/ -55°C < TA < +125°C unless otherwise specified	Group A subgroups 	Limits Min Max	Unii
LO OUTPUT					
Off leakage current	IL	V(pin 5) = 40 V	1, 2, 3	1.0	μА
On voltage	V _{ON} (LO)	I _L = -5.0 mA	1, 2, 3	0.5	٧
Supply current	Is	V(pin 8) = 5.0 V	1, 2, 3	3.0	mA
		V(pin 8) = 20 V	1, 2, 3	 15 	mA
Reset minimum pulse width	t _{W1}	Amplitude = 3.0 V, T _A = +25°C, See figure 3	9	300	ns
Delay from reset to LO output	t _{D(OFF)}	$R_L = 470\Omega$ to V_S , $T_A = +25^{\circ}C$, See figure 3	9	600	ns
LO input minimum pulse width	t _{W2}	Amplitude = 200 mV, T _A = +25°C, See figure 3	9	300	ns
Delay from LO input to LO output	FB(6N)	Amplitude = 200 mV, $ R_L = 470\Omega$ to V_S , $ T_A = +25^{\circ}C$ See figure 3) 9 		ns
Delay from HI input to LO output	to(ON)	Amplitude = 200 mV, V _{CM} = 5.0 V, I _A = +25°C, See figure 3	 y 	900	ns
Delay from HI output to LO output		LO CM input = 200 mV, T _A = +25 C, See figure 3	9	60	ns

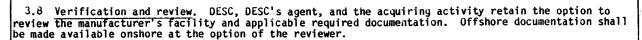
 $[\]frac{1}{2}$ All measurements apply at $V_S = +5.0$ V and with the circuit unlatched or reset, unless otherwise specified.

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- 4. QUALITY ASSURANCE PROVISIONS
- 4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with section 4 of MIL-M-38510 to the extent specified in MIL-STD-883 (see 3.1 herein).
- 4.2 Screening. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:
 - a. Burn-in test (method 1015 of MIL-STD-883).
 - (1) Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.5 herein).
 - (2) $T_A = +125$ °C, minimum.
 - b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.
- 4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with method 5005 of MIL-STD-883 including groups A, ප, C, and D inspections. The following additional criteria shall apply.
 - 4.3.1 Group A inspection.
 - a. Tests shall be as specified in table II herein.
 - b. Subgroups 5, 6, 7, 8, 10, and 11 in table I, method 5005 of MIL-STD-3d3 shall be omitted.
 - 4.3.2 Groups C and D inspections.
 - a. End-point electrical parameters shall be as specified in table II herein.
 - b. Steady-state life test (method 100% of MIL-STD-883) conditions:
 - (1) Test condition A, 3, 0, or D using the circuit submitted with the certificate of compliance [see 3.5 herein).
 - (2) In a *125°C, minimum.
 - (3) Tast duration: 1,000 hours, except as permitted by appendix B of MIL-M-38510 and method 1005 of MIL-STD-883.

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TABLE II. Electrical test requirements.

 MIL-STD-883 test requirements 	 Subgroups (per method 5005, table I)
 Interim electrical parameters (method 5004)	1
 Final electrical test parameters (method 5004)	1*, 2, 3, 9
 Group A test requirements (method 5005)	1, 2, 3, 4, 9
 Groups C and D end-point electrical parameters (method 5005)	1

^{*} PDA applies to subgroup 1.

5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-M-38510.

6. NOTES

- 6.1 Intended use. Microcircuits conforming to this drawing are intended for use when military specifications do not exist and qualified military devices that will perform the required function are not available for OEM application. When a military specification exists and the product covered by this drawing has been qualified for listing on QPL-38510, the device specified herein will be inactivated and will not be used for new design. The QPL-38510 product shall be the preferred item for all applications.
- 6.2 Replaceability. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.
- 6.3 Comments. Comments on this drawing should be directed to DESC-ECS, Dayton, Ohio 45444, or telephone 513-296-5375.

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6.4 Approved source of supply. An approved source of supply is listed herein. Additional sources will be added as they become available. The vendor listed herein has agreed to this drawing and a certificate of compliance (see 3.5 herein) has been submitted to DESC-ECS.

Military drawing part number	Vendor CAGE number	 Vendor <u>1</u> / similar part number
5962-8684901PX	34333 	 SG1549Y/883B

1/ Caution. Do not use this number for item acquisition Items acquired by this number may not satisfy the performance requirements of this drawing.

Vendor CAGE number

34333

Vendor name and address

Silicon General, Incorporated 11651 Monarch Street Garden Grove, CA 92641

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